IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Arup Bhattacharyya

Title:

HIGH-PERFORMANCE ONE-TRANSISTOR MEMORY CELL

Docket No.:

1303.111US1

Filed:

July 2, 2003

Examiner:

Unknown

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Serial No.: 10/612793

Due Date: N/A

Group Art Unit: 2811

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

We are transmitting herewith the following attached items (as indicated with an "X"):

- \underline{X} A return postcard.
- X A Communication Concerning Related Applications (1 pg.).
- X An Information Disclosure Statement (2 pgs.), Form 1449 (2 pgs.), and copies of 20 cited documents.

If not provided for in a separate paper filed herewith, Please consider this a PETITION FOR EXTENSION OF TIME for sufficient number of months to enter these papers and please charge any additional fees or credit overpayment to Deposit Account No. 19-0743.

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.

Customer Number 21186

Atty: Marvin L. Beekman

Reg. No. 38,377

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 35 day of February, 2004.

Nome

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.

(GENERAL)

<u>S/N 10/612793</u>

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Arup Bhattacharyya

Examiner: Unknown

PATENT

Serial No.:

10/612793

Group Art Unit: 2811

Filed:

July 2, 2003

Docket: 1303.111US1

Xitle:

HIGH-PERFORMANCE ONE-TRANSISTOR MEMORY CELL

COMMUNICATION CONCERNING RELATED APPLICATION(S)

mmissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Applicant would like to bring to the Examiner's attention the following related application(s) in the above-identified patent application:

Serial/Patent No.	Filing Date	Attorney Docket	<u>Title</u>
10/232855	August 30, 2002	1303.072US1	GATED LATERAL THYRISTOR-BASED
			RANDOM ACCESS MEMORY CELL
			(GLTRAM)
10/232848	August 30, 2002	1303.073US1	ONE-DEVICE NON-VOLATILE
			RANDOM ACCESS MEMORY CELL
10/232846	August 30, 2002	1303.080US1	ONE TRANSISTOR SOI NON-VOLATILE
			RANDOM ACCESS MEMORY CELL
10/425483	April 29, 2003	1303.105US1	ONE TRANSISTOR SOI NON-VOLATILE
	•		RANDOM ACCESS MEMORY CELL

Respectfully submitted,

ARUP BHATTACHARYYA

By Applicant's Representatives,

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.

P.O. Box 2938

Minneapolis, MN 55402

(612) 373-6960

Date	2	-25	-04

Marvin I Reekma

Reg. No. 38,377

<u>CERTIFICATE UNDER 37 CFR 1.8:</u> The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this <u>Assertion</u> day of <u>February</u>, 2004.

Judish Dens

Signature

S/N 10/612793 **PATENT**

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Arup Bhattacharyya Examiner: Unknown Serial No.: 10/612793 2811

Group Art Unit:

Filed: July 02, 2003 Docket: 1303.111US1 HIGH-PERFORMANCE ONE-TRANSISTOR MEMORY CELL

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

itle:

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 et. seq., the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicant respectfully requests that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicant requests that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicant with the next official communication.

Pursuant to 37 C.F.R. §1.97(b), it is believed that no fee or statement is required with the Information Disclosure Statement. However, if an Office Action on the merits has been mailed, the Commissioner is hereby authorized to charge the required fees to Deposit Account No. 19-0743 in order to have this Information Disclosure Statement considered.

Filing Date: July 02, 2003

Title: HIGH-PERFORMANCE ONE-TRANSISTOR MEMORY CELL

Dkt: 1303.111US1

The present application is either a U.S. national patent application filed after June 30, 2003 or an international application that entered the national stage under 35 U.S.C. § 371 after June 30, 2003. Thus, Applicant believes that the U.S. Patent & Trademark Office has waived the requirement under 37 C.F.R. 1.98 (a)(2)(i) for submitting a copy of each cited U.S. patent and each U.S. patent application publication. The waiver is provided in a pre-OG notice from the U.S. Patent & Trademark Office entitled "Information Disclosure Statements May Be Filed Without Copies of U.S. Patents and Published Applications in Patent Applications filed after June 30, 2003" and dated July 11, 2003. Applicant acknowledges the requirement to submit copies of foreign patent documents and non-patent literature in accordance with 37 C.F.R. 1.98(a)(2).

The Examiner is invited to contact the Applicant's Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,

ARUP BHATTACHARYYA

By his Representatives,

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A. P.O. Box 2938
Minneapolis, MN 55402

(612) 373-6960

Date 2-25-04

y / L L

Reg. No. 38,377

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this day of February, 2004.

Judish Dent

Signature

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary E JC)

Complete if Known	
Application Number	10/612793
Filing Date	July 2,2003
First Named Inventor	Bhattacharyya, Arup
Group Art Unit	2811
Examiner Name	Unknown

Sheet 1 of 2

Attorney Docket No: 1303.111US1

	US PATENT DOCUMENTS					
Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
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	US-2003/0072126	04/17/2003	Bhattacharyya,Arup	361	311	08/30/2001
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Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	T²
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EXAMINER

DATE CONSIDERED

PTO/SB/08A(10-01)
Approved for use through 10/31/2002. OMB 651-0031
US Patent & Trademark Office: U.S. DEPARTMENT OF COMMERCE

Substitute for form 1449A/PTO	Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number of Complete if Known		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Application Number	10/612793	
(Use as many sheets as necessary)	Filing Date	July 2,2003	
	First Named Inventor	Bhattacharyya, Arup	
	Group Art Unit	2811	
	Examiner Name	Unknown	
Sheet 2 of 2	Attorney Docket No: 1	303.111US1	

		OTHER DOCUMENTS NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog,etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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EXAMINER

DATE CONSIDERED